Amendments to the Specification:

Please replace the paragraph which appears on page 4 at lines 4-8 with the following amended paragraph:

Referring to FIG. 3, a portion of the probe card 16 that mates with the test head [[12]]14 includes the coaxial connectors 18, 20 and alignment apertures 24, 26. The apertures 24, 26 may advantageously be tapered to assist in aligning the test head 14 to the probe card 16 as more fully explained below.

Please replace the paragraph which appears on page 4 at lines 9-13 with the following amended paragraph:

Referring to FIG. 4, the bottom surface of the test head [[16]]14 that mates with the probe card 16 includes the coaxial connectors 28, 30, the alignment pins 32, 34 and the de-mating devices 36, 38. The alignment pins 32, 34 may be advantageously tapered to assist in aligning the test head 14 with the probe card 16.